Applicant(s)/Patent Under Application/Control No. Reexamination 09/751,799 KNAPPE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2642 Benny Q. Tieu **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 709/204 06-2002 US-6,408,327 McClennon et al. 709/204 US-2002/0013813 01-2002 MATSUOKA, SHINYA В US-C D US-US-Ε US-F G US-USн US-1 J US-US-K US-L М US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U X

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